


<b>Search Notes</b>  	<b>Application/Control No.</b>  10736698	<b>Applicant(s)/Patent Under Reexamination</b>  CHEN ET AL.
	<b>Examiner</b>  GERMAN VIANA DI PRISCO	<b>Art Unit</b>  2617

SEARCHED			
Class	Subclass	Date	Examiner
370	328	4/3/2008	GV

SEARCH NOTES		
Search Notes	Date	Examiner
EAST Image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (see attached search strategy)	4/3/2008	GV
Inventor name and Assignee search in PALM ExPO and EAST	4/3/2008	GV
EPO Database( <a href="http://ep.espacenet.com">http://ep.espacenet.com</a> )	4/3/2008	GV
Consulted with Rafael Perez-Gutierrez	4/3/2008	GV
Updated search	10/15/2008	GV

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

--	--